



# Test Beam and Lab Results of ATLAS Sensors with Modified Pixel Implantations

#### 8th Beam Telescopes and Test Beams Workshop

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#### **REINER Pixel Design** REdesigned, INnovative, Exciting and Recognizable

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- Pixel size: 250 µm x 50 µm (same as for IBL, innermost detector of the ATLAS Experiment)
- N-in-n wafer process
- Sensor thickness 200 µm
- Moderated p-spray
- Six modified designs
  - Three divided in 4/10/18 sub implants
  - One with rectangular corners
  - Two with narrowed n<sup>+</sup> implant

V0: IBL-standard V1-V6: modified Blue: n<sup>+</sup> Grey: metal Green: Nitride openings



## **REINER Pixel Sensors**



- Eight structures on one sensor
  - Two IBL designs (V0 & 05)
  - Six modified designs
- Each structure consists of 10 columns x 336 rows with the same design
- Separate HV pads
- Individual guard rings
- Readout by one FE-I4





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Test Beam:

- DESY and CERN
- 5GeV Electron or 120GeV Pion Beam
- EUDET-type telescope
- Cooled setup
- Irradiated REINER sensors measured at different tuning, positions and voltages



This talk focuses on the results of the irradiated Sensor R3: neutron irradiated to  $5e15n_{eq}/cm^2$  in Ljubljana

## **TB Results for irrad. Sensor R3**

- To prevent influence of guard rings: Only four innermost columns of each pixel design
- When sensor fully depleted: No differences in the efficiency between voltage steps
- To observe differences of the pixel designs use lower voltages (here: 300V)





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**V3** 

**V1** 

**V5** 

**V2** 

**V6** 

**V**4

**V0** 

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- Projection of the track position into one pixel: In-Pixel Maps





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Efficiency Map R3 Tuning: 1600e, 6ToT@20ke Row 300 0.9 -05V6 V4V3 V5V0 V2 0.8 250 0.7 200 0.6 0.5 150 0.4 100 0.3 0.2 50 0.1 0 20 30 70 10 40 50 60 Column 50 40 30 20 10 0 50 100 150 200 250





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Tuning: 1600e, 6ToT@20ke



### Annealing Results of R3 at 300V

- Annealing steps:
  3h and 2h at 80°C (long term)
- Efficiencies of standard designs dropped
- Efficiencies of pixel designs with smaller implantation (V5 and V6) increased
- With longer annealing times an increase in efficiency of pixel designs V5 and V6 is observed





## Annealing Results of R3 at 300V





8th BTTB, Mareike Wagner

## **Charge Collection Measurement**





## **Module Preparation**



Target:

Metal free area to inject laser

- Etch HV pad with sodium hydroxide solution:
   One drop per HV pad
- After ~5 min metal is removed
- Rinse with water



## Laser Intensity

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Tuning: 1600e, 6ToT@20ke Bias: 400V Laser: 908nm



- Depending on laser intensity the measured mean ToT changes
- Large difference between different Pixel designs
- Optimal laser intensity:
  - For V5 = 8.65
  - For V0 = 8.80-8.85



 $\rightarrow$  No common laser intensity for V0 and V5 can be found

## **Results Charge Collection**



- Mean ToT for Pixel Design V5 908nm laser ToT Small Side [um] 100 Laser intensity: 8.65aU 80 Trigger: 500Hz 6 Scan area: 60 5 370µm x 100µm 4 40 Step width: 8µm 3 Only cluster size 1 2 20 0 50 100 150 200 250 300 350 0 Long Side [um]
- Hot spots with higher ToT values are visible



## Conclusion

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- Test beam results of neutron irrad. sensor: Efficiencies of the pixel designs with narrowed implantation increase with annealing
- DESY TB results do not provide enough resolution to investigate the region with higher efficiency inside the pixel
- Charge multiplication could result in higher efficiencies
- Investigate the charge collected by the sensor after laser injection
- Regions with higher ToT values (charge) are visible in this laser induced charge collection measurements

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- Improve the setup by fixing the module holder and insulating box to the PI-stage
- Measure the amount of photons in dependence of the laser intensity
- Measure non-annealed neutron irradiated sensors (1e15n<sub>eq</sub>/cm<sup>2</sup> and 5e15n<sub>eq</sub>/cm<sup>2</sup>) with the improved setup in small annealing steps



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